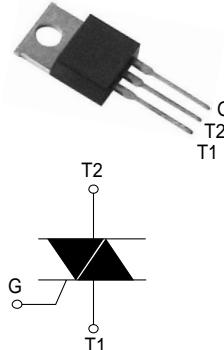
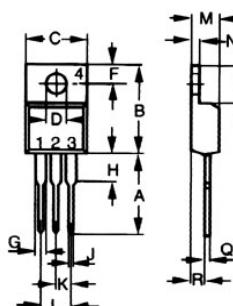


BTB/BTA10

Discrete Triacs(Non-Isolated/Isolated)



Dimensions TO-220AB



Dim.	Inches		Milimeter	
	Min.	Max.	Min.	Max.
A	0.500	0.550	12.70	13.97
B	0.580	0.630	14.73	16.00
C	0.390	0.420	9.91	10.66
D	0.139	0.161	3.54	4.08
E	0.230	0.270	5.85	6.85
F	0.100	0.125	2.54	3.18
G	0.045	0.065	1.15	1.65
H	0.110	0.230	2.79	5.84
J	0.025	0.040	0.64	1.01
K	0.100	BSC	2.54	BSC
M	0.170	0.190	4.32	4.82
N	0.045	0.055	1.14	1.39
Q	0.014	0.022	0.35	0.56
R	0.090	0.110	2.29	2.79

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter			Value	Unit
I _T (RMS)	RMS on-state current (full sine wave)	TO-220AB	T _c = 105°C	10	A
I _{TSM}	Non repetitive surge peak on-state current (full cycle, T _j initial = 25°C)	F = 60 Hz	t = 16.7 ms	105	A
		F = 50 Hz	t = 20 ms	100	
I ² t	I ² t Value for fusing	tp = 10 ms		55	A ² s
dI/dt	Critical rate of rise of on-state current I _G = 2 x I _{GT} , tr < 100 ns	F = 120 Hz	T _j = 125°C	50	A/μs
V _{DSM} /V _{RSM}	Non repetitive surge peak off-state voltage	tp = 10 ms	T _j = 25°C	V _{DRM} /V _{RRM} + 100	V
I _{GM}	Peak gate current	tp = 20 μs	T _j = 125°C	4	A
P _{G(AV)}	Average gate power dissipation		T _j = 125°C	1	W
T _{stg} T _j	Storage junction temperature range Operating junction temperature range			- 40 to + 150 - 40 to + 125	°C

ELECTRICAL CHARACTERISTICS (T_j = 25°C, unless otherwise specified)

■ SNUBBERLESS™ and LOGIC LEVEL(3 Quadrants)

Symbol	Test Conditions	Quadrant	BTA/BTB		Unit
			CW	BW	
I _{GT} (1)	V _D = 12 V R _L = 33 Ω	I - II - III	MAX.	35	mA
V _{GT}		I - II - III	MAX.	1.3	
V _{GD}	V _D = V _{DRM} R _L = 3.3 kΩ T _j = 125°C	I - II - III	MIN.	0.2	V
I _H (2)	I _T = 500 mA		MAX.	35	mA
I _L	I _G = 1.2 I _{GT}	I - III	MAX.	50	
		II		60	
dV/dt (2)	V _D = 67 % V _{DRM} gate open T _j = 125°C	MIN.	500	1000	V/μs
(dI/dt)c (2)	Without snubber T _j = 125°C	MIN.	5.5	9.0	A/ms



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■ STANDARD (4 Quadrants)

Symbol	Test Conditions	Quadrant		Value	Unit
I _{GT} (1)	V _D = 12 V R _L = 33 Ω	I - II - III IV	MAX.	50 100	mA
V _{GT}		ALL	MAX.	1.3	V
V _{GD}	V _D = V _{DRM} R _L = 3.3 Ω T _j = 125°C	ALL	MIN.	0.2	V
I _H (2)	I _T = 500 mA	I - III - IV II	MAX.	50	mA
I _L			MAX.	50 100	mA
dV/dt (2)	V _D = 67 % V _{DRM} gate open T _j = 125°C		MIN.	400	V/μs
(dV/dt)c (2)	(dI/dt)c = 4.4 A/ms T _j = 125°C		MIN.	10	V/μs

STATIC CHARACTERISTICS

Symbol	Test Conditions		Value	Unit	
V _{TM} (2)	I _{TM} = 14 A t _p = 380 μs	T _j = 25°C	MAX.	1.55	V
V _{to} (2)	Threshold voltage	T _j = 125°C	MAX.	0.85	V
R _d (2)	Dynamic resistance	T _j = 125°C	MAX.	40	mΩ
I _{DRM} I _{RRM}	V _{DRM} = V _{RRM}	T _j = 25°C	MAX.	5	μA
		T _j = 125°C		1	mA

Note 1: minimum IGT is guaranteed at 5% of IGT max.

Note 2: for both polarities of A2 referenced to A1

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
R _{th(j-c)}	Junction to case (AC)	1.5	°C/W
R _{th(j-a)}	Junction to ambient	60	°C/W

PRODUCT SELECTOR

Part Number	Voltage (xxx)		Sensitivity	Type	Package
	200 V ~ 1000 V				
BTBV/BTA10	X	X	50 mA	Standard	TO-220AB

OTHER INFORMATION

Part Number	Marking	Weight	Base quantity	Packing mode
BTB/BTA10	BTB/BTA10	2.3 g	250	Bulk



BTB/BTA10

Discrete Triacs(Non-Isolated/Isolated)

Fig. 1 Maximum power dissipation versus RMS on-state current (full cycle).

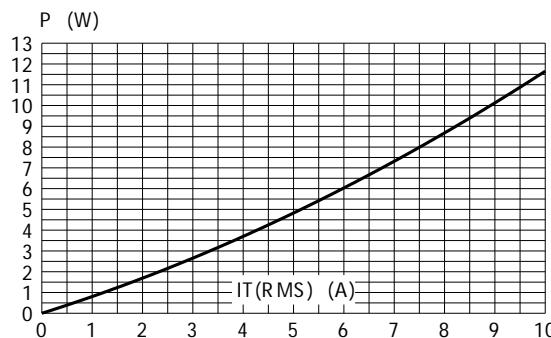


Fig. 2 RMS on-state current versus case temperature (full cycle).

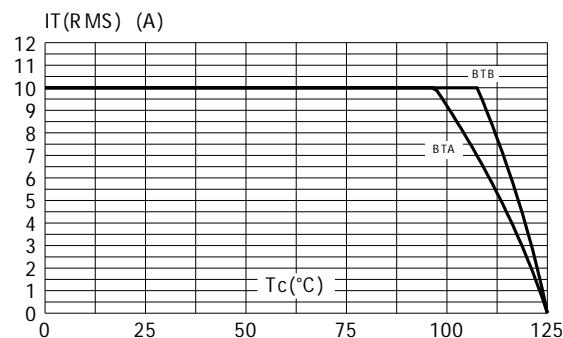


Fig. 3 Relative variation of thermal impedance versus pulse duration.

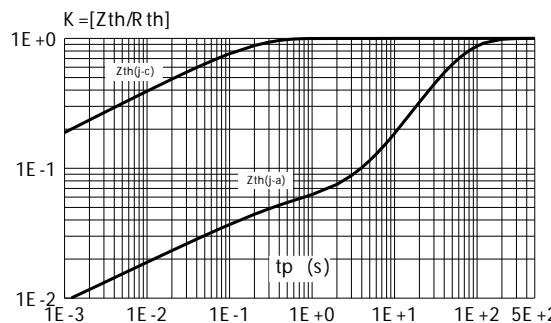


Fig. 5 Surge peak on-state current versus number of cycles.

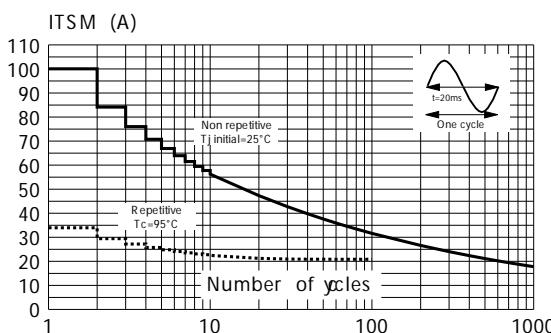


Fig. 4 On-state characteristics (maximum values).

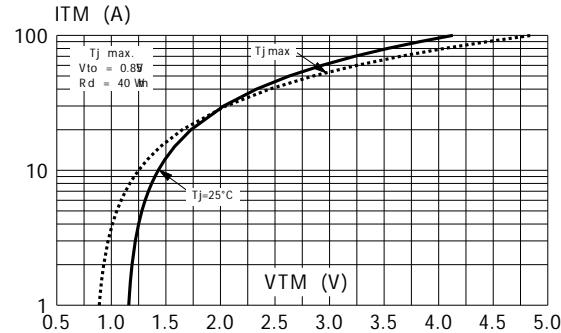
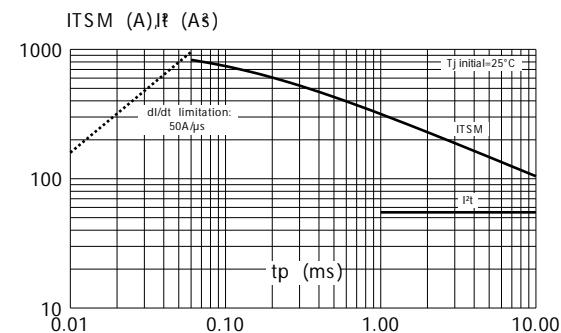


Fig. 6 Non-repetitive surge peak on-state current for a sinusoidal pulse with width tp < 10ms, and corresponding value of I²t.



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Discrete Triacs(Non-Isolated/Isolated)

Fig. 7 Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

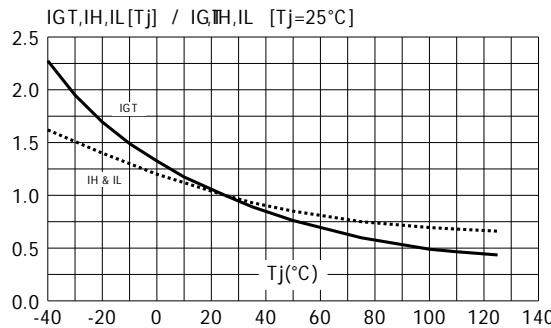


Fig. 8 Relative variation of critical rate of decrease of main current versus (dV/dt)c (typical values).

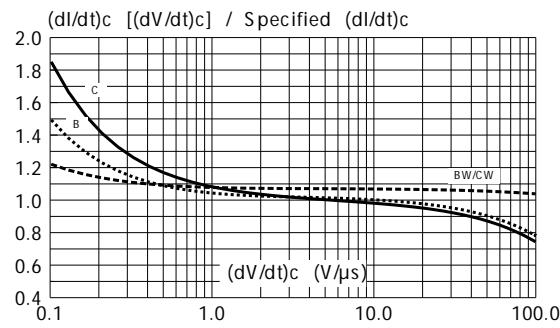


Fig. 9 Relative variation of critical rate of decrease of main current versus junction temperature.

